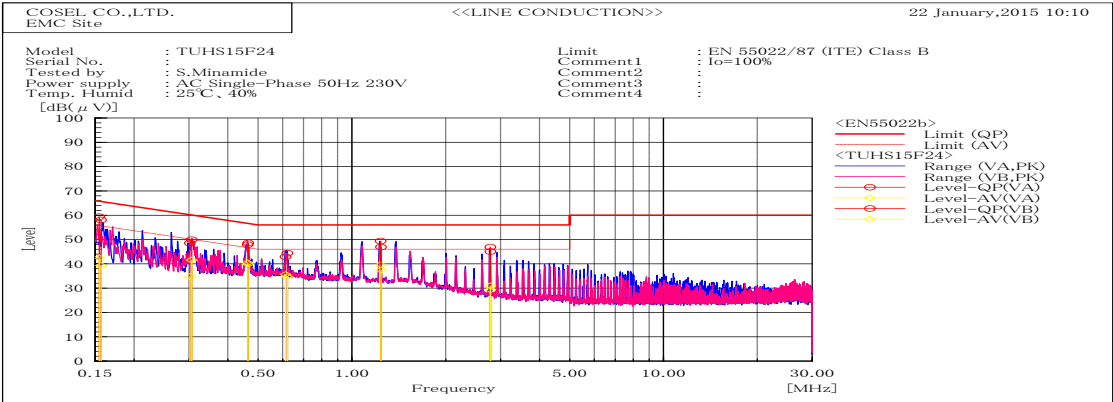
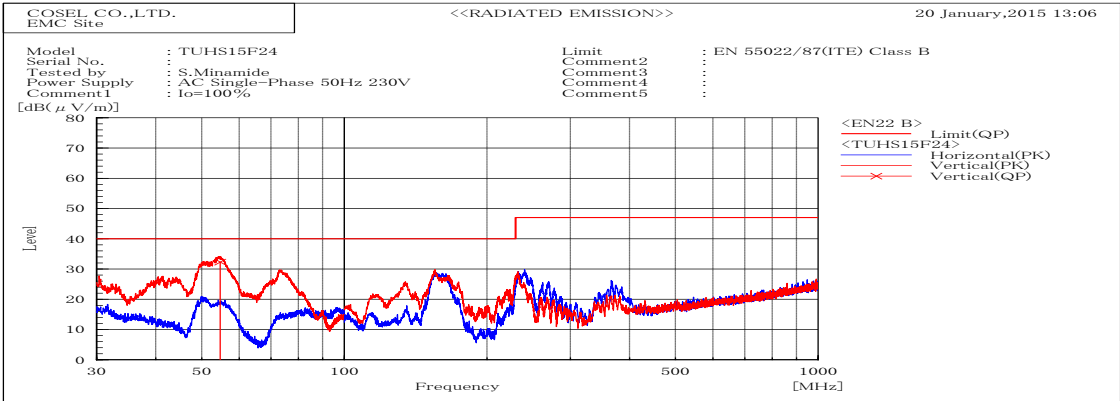


DATA SHEET		Date	26-Feb-15
Model	TUHS15F24	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Minamide



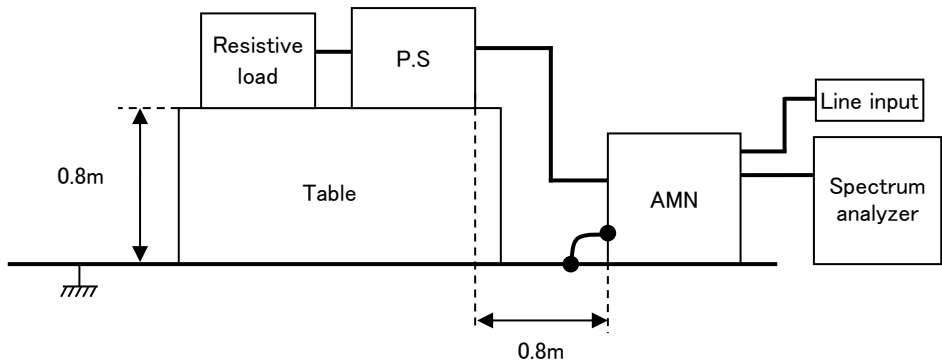
Frequency MHz	Harm	Line Phase	Reading dB(μV)		Factor dB(1/m)	Level dB(mW)		Limit dB(mW)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.15466		VB	39.1	22.2	20.3	59.4	42.5	65.7	55.7	6.3	13.2	Pass	
0.15677		VA	37.7	19	20.3	58	39.3	65.6	55.6	7.6	16.3	Pass	
0.30207		VA	28.3	14.6	20.2	48.5	34.8	60.2	50.2	11.7	15.4	Pass	
0.30606		VB	29.8	21.4	20.1	49.9	41.5	60.1	50.1	10.2	8.6	Pass	
0.4634		VB	27.8	20.3	20.1	47.9	40.4	56.6	46.6	8.7	6.2	Pass	
0.46508		VA	28.5	19.7	20.1	48.6	39.8	56.6	46.6	8	6.8	Pass	
0.61305		VB	22.7	15.4	20.2	42.9	35.6	56	46	13.1	10.4	Pass	
0.62092		VA	24.2	14.5	20.2	44.4	34.7	56	46	11.6	11.3	Pass	
1.23931		VA	26.7	17.3	20.2	46.9	37.5	56	46	9.1	8.5	Pass	
1.23634		VB	29.2	19.4	20.2	49.4	39.6	56	46	6.6	6.4	Pass	
2.78375		VB	24.6	10.5	20.4	45	30.9	56	46	11	15.1	Pass	
2.78398		VA	26.5	9	20.4	46.9	29.4	56	46	9.1	16.6	Pass	



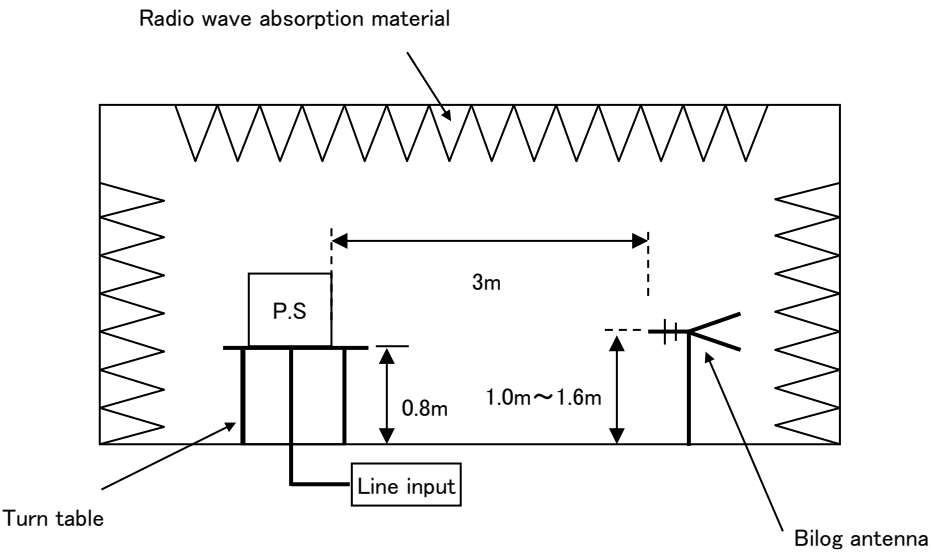
Frequency MHz	Polariz ation	Stabilit y	Reading dB(μV)	Factor dB(1/m)	Level dB(μV/m)	Limit dB(μV/m)	Margin dB	Pass/ Fail	Remark
			QP		QP	QP	QP		
54.713	V	Stable	56.2	-23.9	32.3	40	7.7	Pass	

DATA SHEET		Date	26-Feb-15
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Minamide

1. Line conduction



2. Radiated emission



Conditions

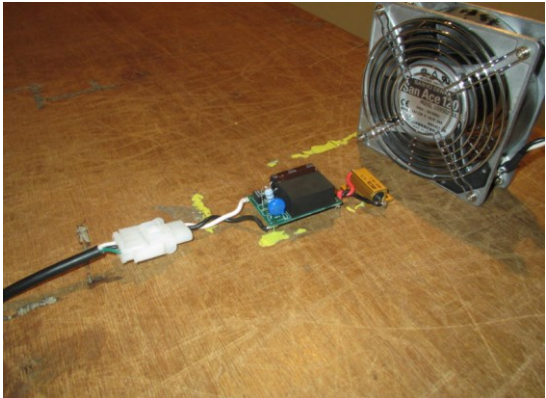
Test: EMI
Model Name: TUHS15F□□

○ Photographs of Test Set-Up

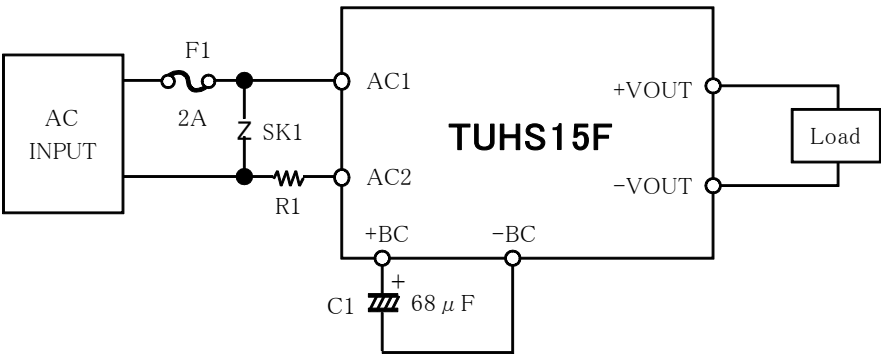
LINE CONDUCTION



RADIATED EMISSION



○ Test circuit



F1: SLT250V2A (Nippon Seisen)	2A
R1: CW3CJ (KOA)	10Ω
SK1: S10K385E2K1 (TDK EPCOS)	

Fig.1 Testing circuitry